PCN Number:		20181129000.1					<b>PCN Date:</b> Dec 18, 2018					
Title:	Qualification of devices	Qualification of Mold Compound and Mount Compound for selected TSSOP package devices						ected TSSOP package				
Proposed 1 <sup>st</sup> Ship Dat		e:	e: Mar 18, 2019			Estimated Sample Availability:			Provided upon Request			
Chan	ge Type:											
	ssembly Site			Design				Wafer Bump Site				
	ssembly Process				Data Sh	neet			Wafer Bump Material			
⊠ A	ssembly Materials			F	Part nu	mber chang	je		Wafer Bump Process			
M	lechanical Specifica	ation			Test Sit				Wafer Fab Site			
Packing/Shipping/Labe			ıg		Test Pro	ocess			Wafer Fab Materials			
	<u> </u>			•					Wafer Fab Process			
					PCN I	Details						
Descr	ription of Change	): :										
Mount	Texas Instruments is pleased to announce the qualification of Mold Compound 4211471 and Mount Compound 4147858 for select TSSOP package devices. Devices will remain in their current assembly facility and material differences are shown in the following table:											
				Change From: Change To:								
			4042500			ge i ioiii.						
	nt Compound				404	2500			4147858			
	nt Compound I Compound			42	404							
Mold				42	404	2500			4147858			
Mold	l Compound			42	404	2500			4147858			
Reaso Contin	on for Change: nuity of supply.	Fit,	Form,		404 209002	2500 , 4206193	Reliab	ility (	4147858			
Reaso Contin	on for Change: nuity of supply. ipated impact on	Fit,	Form,		404 209002	2500 , 4206193	Reliab	ility (	4147858 4211471			
Reason Continuation Anticinuation None.	on for Change: nuity of supply. ipated impact on	Mate	erial D	Fund	404 209002 ction,	2500 , 4206193 <b>Quality or</b>	Reliab	ility (	4147858 4211471			
Reason Continuation None.  Antician None.	on for Change: nuity of supply. ipated impact on	Mate	erial D  Ma fro pro rep no	Fundaterial of production orts impa	ction, ration I Declar oduction ion rele can be act to th	Quality or Pon data and ease. Upon obtained fi	roduct will be product om the meetin	Conte availa ction r	4147858 4211471  (positive / negative):  ent reports are driven able following the release the revised co-Info website. There is rent regulatory			
Reason Continuation None.  Anticinuation None.	on for Change: nuity of supply. ipated impact on ipated impact on No Impact to the	Mato	erial D Ma fro pro rep no cor	Fundaterial of production orts impartments	ction,  ration  I Declar oduction ion rele can be act to the	Quality or rations or Pon data and ease. Upon obtained fine material quirements	roduct will be product om the meetin with th	Conte availa ction r	4147858 4211471  (positive / negative):  ent reports are driven able following the release the revised co-Info website. There is rent regulatory			
Reason Continuation None.  Anticinuation None.	ipated impact on No Impact to the Material Declaratio	Mato	erial D Ma fro pro rep no cor	Fundaterial of production orts impa	ction,  ration  I Declar oduction ion rele can be act to the	Quality or rations or Pon data and ease. Upon obtained fine material quirements	roduct will be product om the meetin with th	Conte availa ction r	4147858 4211471  (positive / negative):  ent reports are driven able following the release the revised co-Info website. There is rent regulatory			
Reason Continuation None.  Antici  Antici  Change None.	ipated impact on No Impact to the Material Declaratio	Mato	erial D Ma fro pro rep no cor	Fundaterial of production orts impa	ction,  ration  I Declar oduction ion rele can be act to the	Quality or rations or Pon data and ease. Upon obtained fine material quirements	roduct will be product om the meetin with th	Conte availa ction r	4147858 4211471  (positive / negative):  ent reports are driven able following the release the revised co-Info website. There is rent regulatory			
Reason Continuation None.  Anticinuation None.  Change None.  Produ	ipated impact on No Impact to the Material Declaration of	n Mate	erial D Ma fro pro rep no cor	Fundaterial of production orts imparting impliance.	ction, ration I Declar oduction ion rele can be act to the nce rec	Quality or rations or Pondata and ease. Upon obtained fine material quirements	roduct will be product om the meetin with th	Conte availa ction r TI Ec g cur is PCN	4147858 4211471  (positive / negative):  ent reports are driven able following the release the revised co-Info website. There is rent regulatory			
Reason Continuation None.  Anticipation None.  Change None.  Produ	ipated impact on No Impact to the Material Declaration uct Affected:	n Mate	erial D Ma fro pro rep no cor	Function production production impartments impartments in research	ction,  ration  I Declar oduction ion releact to the recession recession recession.	Quality or rations or Pon data and ease. Upon obtained fine material quirements  from this	roduct will be product om the meetin with th PCN:	Conte availa ction r TI Ec g cur is PCN	4147858 4211471  (positive / negative):  ent reports are driven able following the release the revised co-Info website. There is rent regulatory			
Reason Continuation None.  Anticipation None.  Change None.  Produ	ipated impact on No Impact to the Material Declaration of	Mate n ADS:	erial D Ma fro pro rep no cor	Fundaterial of production orts imparaged impliants of the content	ction,  ration  I Declar oduction ion releact to the recession recession recession.	Quality or rations or Pondata and ease. Upon obtained fine material quirements	roduct will be product om the meetin with th PCN: 014PW	Conte availa ction r TI Ec g cur is PCN	4147858 4211471  (positive / negative):  ent reports are driven able following the release the revised co-Info website. There is rent regulatory			

## **Qualification Report**

Approve Date 26-Aug-2016

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: 8BT245MDGGEP	Qual Device: 8X512DGGR	Qual Device: ADS1259BIPWR	Qual Device: CLVC374APWR	Qual Device: E8722DGGR	Qual Device: SN200708045DAR	Qual Device: SN65MLVD129DGG
AC	Autoclave 121C	96 Hours	3/231/0	-	-	-	3/231/0	3/231/0	1/77/0
ED	Electrical Characterization	Per Datasheet Parameters	-	-	-	Pass	-	-	-
HAST	Biased HAST, 130C/85%RH	192 Hours	-	-	-	-	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-	-
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	3/231/0	-	-	-	-	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass	Pass	Pass	Pass
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	1/77/0
VM	Visual Quality Reliability Inspection	Post Autoclave 96 Hours	-	-	-	-	-	3/6/0	-
VM	Visual Quality Reliability Inspection	Post Biased HAST 96 Hours	-	-	-	-	-	-	-
VM	Visual Quality Reliability Inspection	Post Temp Cycle 500 Cycles	-	3/6/0	-	-	-	3/6/0	-

Туре	Test Name / Condition	Duration	Qual Device: THS4524IDBTR	Qual Device: TPS2111PWR	Qual Device: TPS23861PWR	Qual Device: TPS43000PW	QBS Package Reference: SN65C1168PWR	QBS Package Reference: TA S5086DBT	QBS Package Reference: TPIC1353DBTRG4
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	-	-	3/231/0	3/231/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	-	-	-	-	-	-	-
HAST	Biased HAST, 130C/85%RH	192 Hours	-	-	3/231/0	-	3/227/0	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-	3/227/0	3/231/0	3/231/0
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	-	3/231/0	3/231/0	3/231/0	3/231/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass	Pass	Pass	Pass
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0	-	3/231/0	3/230/0	3/231/0	3/231/0
VM	Visual Quality Reliability Inspection	Post Autoclave 96 Hours	3/6/0	3/6/0	-	-	-	-	-
VM	Visual Quality Reliability Inspection	Post Biased HAST 96 hours	-	-	3/6/0	-	-	-	-
VM	Visual Quality Reliability Inspection	Post Temp Cycle 500 Cycles	3/6/0	3/6/0	-	3/6/0	-	-	-

- QBS: Qual By Similarity
- Qual Devices qualified at LEVEL1-260CG: E8722DGGR, TPS43000PW, SN200708045DAR , CLVC374APWR, TPS2111PWR, 8X512DGGR, 8BT245MDGGEP, ADS1259BIPWR
- Qual Devices qualified at LEVEL2-260CG: SN65MLVD129DGG, THS4524IDBTR, TPS23861PWR
- Device THS4524IDBTR contains multiple dies.
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com